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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/809,553	JOHNS ET AL.	
Examiner	Art Unit	
Chun-Kuan (Mike) Lee	2181	

SEARCHED			
Class	Subclass	Date	Examiner
710	22-28	9/22/2006	CHUN- KUAN Lee
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
(EAST) US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB Google Inventor search utilizing Palm and East	9/22/2006	etan Kuan Lec.
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